



IEC QUALITY ASSESSMENT SYSTEM (IECQ)

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IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: **IECQ-L DEKRA 16.0002-02**

Issue No.: **8**

Status: **Current**

Additional site to certification: **IECQ-L DEKRA 16.0002**

Initial Date: **2016-08-17**

Supersedes: **IECQ-L DEKRA 16.0002-02 Issue 7**

Issue date: **2026-10-22** Site Added: **2017-12-22**

CB Reference No.: **DEKRA-T5C-003**

Expiration: **2028-08-16**

Applicant: **Integrated Service Technology Inc.**
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The organization, facilities and procedures have been assessed by the IECQ Conformity Assessment Body in accordance with IECQ 03-1 and IECQ 03-6 for issuance of this certificate and found to be in conformity with the applicable requirements of the IECQ Independent Testing Laboratory Assessment Program Requirements Scheme and in respect of the listed standard(s) or specification(s) for the testing of component product under the IECQ:

- **ISO/IEC 17025:2017** - General requirements for the competence of testing and calibration laboratories

Scope:

- Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

- See attached Schedule of Scope

-- Attached schedule(s): IECQ-L DEKRA 16.0002-02-S_1.pdf

Issued
by:

DEKRA Certification B.V.
Meander 1051, Arnhem, Netherlands

<https://www.dekra-product-safety.com/en/about-dekra/locations/europe/netherlands/arnhem>



Authorised person: Rosa Zhou



The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.
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Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L DEKRA 16.0002-02

CB Certificate No.: DEKRA-T5C-003

Schedule Number: IECQ-L DEKRA 16.0002-02-S Rev No.: 8 Revision Date: 2026-10-22 Page 1 of 1

Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

Description test	Standard
Steady-Status Temperature and Humidity Bias Life Test (THB)	JESD22-A101, AEC-Q100, AECQ-101, AEC-Q200, MIL-STD-202
High Humidity High Temp. Reverse Bias (H3TRB)	JESD22-A101, AEC-Q101
Power and Temperature Cycling (PTC)	JESD22-A105, AEC-Q100, AEC-Q101
High Temperature Operation test (HTOL)	JESD22-A108, AEC-Q100, AEC-Q200, MIL-STD-202
Low Temperature Operation test (LTOL)	JESD22-A108
High Temperature Reverse Bias (HTRB)	JESD22-A108, AEC-Q101, MIL-STD-750, MIL-STD-883
High Temperature Gate Bias (HTGB)	JESD22-A108, AEC-Q101
Early Life Failure Rate (ELFR)	JESD22-A108, AEC-Q100
Highly Accelerated Stress Test (HAST)	JESD22-A110, AEC-Q100, AEC-Q101
Electrically Erasable Programmable ROM (EEPROM) Program/Erase Endurance and Data Retention Stress Test (Endurance and Data Retention)	JESD22-A117, AEC-Q100,
Power Cycling	JESD22-A122
NVM Endurance, Data Retention, and Operation Life (EDR)	AEC-Q100
Electromigration (EM)	JEP001, JESD61, JESD87, AEC-Q100,
Stress Migration (SM)	JEP001, JEP139, JESD87, AEC-Q100,
Steady-Status operation life	MIL-STD-750, MIL-STD-883
Wafer/Substrate saw	A00-550-30001
Die Bond	A00-550-30034
Wire Bonding	A00-550-30003 A00-550-30035

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